


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590632	<b>Applicant(s)/Patent Under Reexamination</b>  JENSEN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/15/2008	/YJK/
see enclosed for text-search strategy	9/15/2008	/YJK/
updated - patent databases search - see enclosed for text-search strategy	5/13/2009	/YJK/
updated - patent databases search - see enclosed for text-search strategy	3/9/2010	/YJK/
updated	6/19/2010	/YJK/
updated	9/29/2010	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search - see enclosed for search strategy	3/9/2010	/YJK/

	/Young J Kim/ Primary Examiner.Art Unit 1637
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